

N-Channel 20V (D-S) MOSFET

Description

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low rDS(on) and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

Features

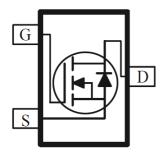
- Low rDS(on) provides higher efficiency and extends battery life
- · Low thermal impedance copper leadframe
- · SOT-23 saves board space
- · Fast switching speed
- · High performance trench technology
- · RoHS compliant package

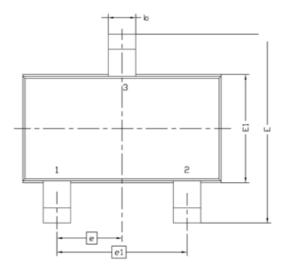
Packing & Order Information

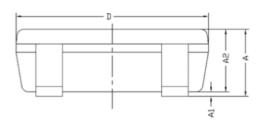
3,000/Reel

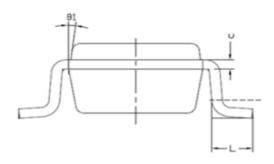


Graphic symbol









Symbol	MILLIMETERS			
Syllibol	MIN	MAX		
Α	8.0	1.2		
A1	0	0.1		
A2	0.7	1.1		
b	0.3	0.5		
С	0.1	0.2		
D	2.7	3.1		
E	2.6	3		
E1	1.4	1.8		
е	0.95 BSC			
e1	1.9 BSC			
L	0.3	0.6		
θ1	7° NOM			



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MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings (Tc=25°C unless otherwise noted)						
Symbol	Parameter	Value	Unit			
V_{DSS}	Drain-Source Voltage	20	V			
V _{GS}	Gate-Source Voltage	±8	V			
1	Continuous Drain Current @ TC=25°C	4.3	Α			
I _D	Continuous Drain Current @ TC=70°C	3.3	Α			
I_{DM}	Pulsed Drain Current	10	Α			
Is	Continuous Source Current (Diode Conduction)	0.46	Α			
P _D	Power Dissipation (TC=25°C)	1.25	W			
	Power Dissipation (TC=100°C)	0.8	W			
T _J /T _{STG}	Operating Junction and Storage Temperature	-55 to +150	°C			

Notes

- a. Surface Mounted on 1" x 1" FR4 Board.
- b. Pulse width limited by maximum junction temperature

Thermal characteristics (Tc=25°C unless otherwise noted)					
Symbol	Parameter	Maximum	Units		
t <= 5 sec	Maximum Junction-to-Ambient(RthJA)	100	°C/W		
Steady State	Maximum Junction-to-Ambient(RthJA)	166	C/VV		

On Characteristics					
Symbol	Test Conditions	Min	Тур.	Max.	Units
V _{GS}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.7			V
R _{DS(ON)}	VGS = 4.5 V, ID = 4.3 A			0.0035	
	VGS = 2.5 V, ID = 3.5 A			0.0050	Ω

Off Characteristics					
Symbol	Test Conditions	Min	Тур.	Max.	Units
V_{GS}	$V_{DS} = V_{GS}$, $I_D = 250\mu A$.7			V
D	VGS = 4.5 V, ID = 4.3 A		30	35	mΩ
R _{DS(ON)}	VGS = 2.5 V, ID = 3.5 A		40	50	
I _{DSS}	$V_{DS} = 16 \text{ V}$, $V_{GS} = 0 \text{ V}$			1	uA
	$V_{DS} = 20 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 55^{\circ}\text{C}$			10	
ID(on)	$V_{GS} = 5 \text{ V}, V_{DS} = 4.5 \text{ V}$	10			Α
I _{GSS}	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$		4	100	nA
V_{SD}	IS = 0.46 A, VGS = 0 V		0.65	1.20	V
Gfs	$V_{DS} = 5 \text{ V}$, $I_D = 3 \text{ A}$		11		S



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Dynamic Characteristics					
Symbol	Test Conditions	Min	Тур.	Max.	Units
Q_g	$V_{DS} = 10 \text{ V}, I_{D} = 2.5 \text{ A},$ $V_{GS} = 3.0 \text{ V}$		7.0		nC
Q_{gs}			11.2		nC
Q_{gd}			1.9		nC

Dynamic Characteristics					
Symbol	Test Conditions	Min	Тур.	Max.	Units
C_{ISS}			700		pF
C _{OSS}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $F = 1.0 \text{MHz}$		175		pF
C _{RSS}	F = 1.0MH2		85		pF
t _{d(on)}			9		ns
t _r	$V_{DD}=10 \text{ V}, I_D=1 \text{ A},$ $R_G=6 \Omega \text{ , } V_{GEN}=4.5 \text{ V}$		11		ns
t _{d(off)}			18		ns
tf			5		ns

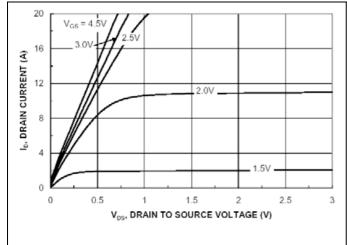
Notes

- a. Pulse test: PW <= 300us duty cycle <= 2%.
- b. Guaranteed by design, not subject to production testing.



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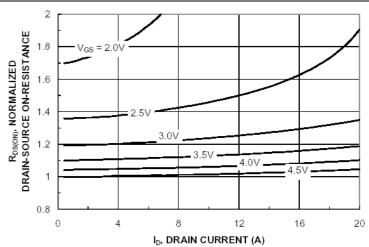


FIG.1-ON REGION CHARACTERISTICS

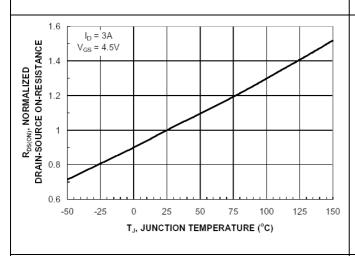


FIG.2-ON-RESISTANCE VARIATION WITH DRAIN CURRENT AND GATE VOLTAGE

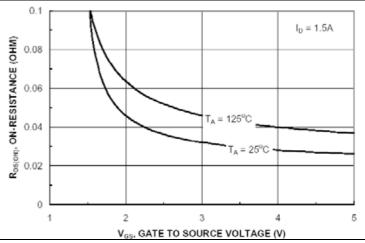


FIG.3-ON-RESISTANCE VARIATION WITH TEMPERATURE

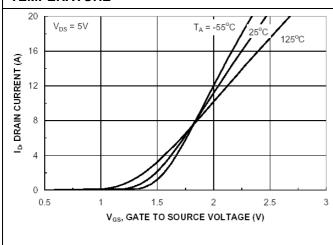


FIG.4-ON-RESISTANCE VARIATION WITH DRAIN CURRENT AND TEMPERATURE

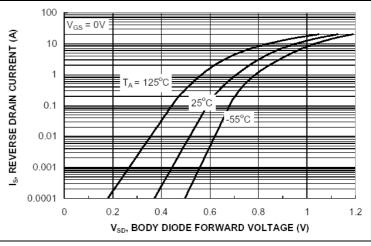


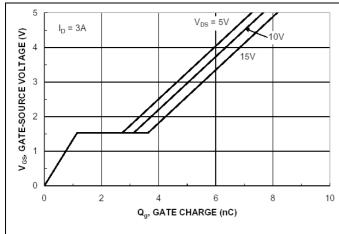
FIG.5-TRANSFER CHARACTERISTICS

FIG.6-GATE THRESHOLD VARIATION WITH TEMPERATURE



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■Characteristics Curve



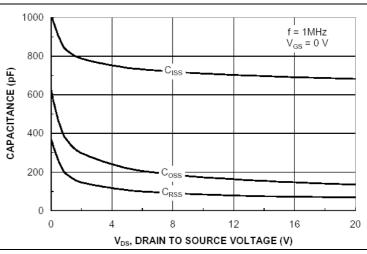


FIG.7-GATE CHARGE CHARACTERISTIC

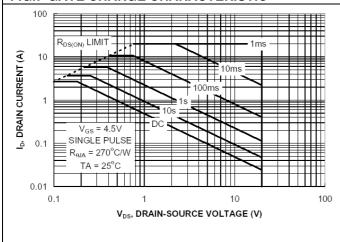


FIG.8-CAPACITANCE CHARACTERISTIC

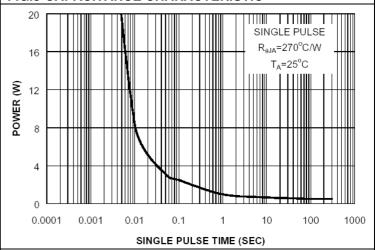


FIG.9-MAXIMUM SAFE OPERATING AREA

FIG.10-BREAKDOWN VOLTAGE VARIATION WITH TEMPERTURE

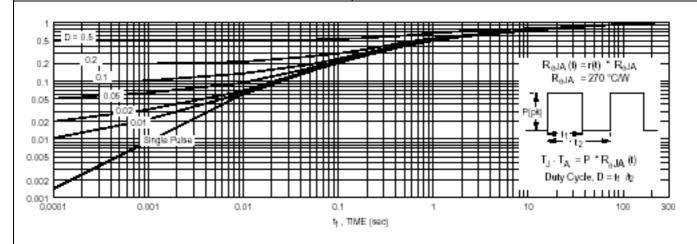


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient themal response will change depending on the circuit board design.

FIG.11-TRANSIENT THERMAL RESPONSE CURVE



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